

Notice of References Cited

Application/Control No.

09/915,984

Applicant(s)/Patent Under
Reexamination
HARTMANN, UDO

Examiner

Paresh Patel

Art Unit

2829

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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	Q					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Non-Destructive, Non-Contacting Test of Si Wafers by Thermore- Flectance" IBM Tech. Disc. Bull. Feb. 1987 (NN87024105)
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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